

VISUAL WALKTHROUGH

12.1 INTRODUCTION

The combinational and sequential digital circuits have been discussed in earlier chapters for performing basic digital operations and other functions, such as multiplexers, comparators, code converters, shift registers and counters, etc. have also been discussed. They are referred to as *fixed-function ICs*, i.e. each one of them performs a specific, fixed function designed by their manufacturers and are manufactured in large quantities to meet the requirements of applications and are readily available.

To design a circuit, a designer can select from the available ICs the most appropriate one working from a block diagram design concept. The design may have to be modified to meet the requirements of these devices. The advantages of this method are:

1. Low development cost,
2. Fast turn around of designs, and
3. Relatively easy to test the circuits

Some of the disadvantages of this method are:

1. Large board space requirements,
2. Large power requirements,
3. Lack of security, i.e. the circuits can be copied by others, and
4. Additional cost, space, power requirements, etc. required to modify the design features.

To overcome the disadvantages of designs using fixed-function ICs, *application specific ICs* (ASICs) have been developed. The ASICs are designed by the users to meet the specific circuit and are produced by an IC manufacturer (*foundry*) as per the specification. Usually, the designs are too complex to be implemented using fixed-function ICs.

The advantages of this method are:

1. Reduced space requirement,
2. Reduced power requirement,

INTRODUCTION

Each chapter begins with an *Introduction* that introduces the topic giving its brief background, importance and contents of the chapter.

SECTIONS & SUB-SECTION

Each chapter has been divided into *Sections and Sub-sections* to present the chapter's subject matter in a logical progression of ideas and concepts.

4.16 LOW-VOLTAGE CMOS LOGIC

Dynamic power dissipation in CMOS logic circuits decreases with the decrease in the reduced power supply voltage helps in making transistors with thinner oxide insulators. This results in smaller transistor geometries. This increases the packing density, i.e. more number of components are placed in a given area. Because of this, the IC manufacturers have produced a number of low-voltage CMOS devices which are commercially available.

The Joint Electronic Device Engineering Council (JEDEC), an IC industry standard, has specified the following standard logic power-supply voltages:

$$3.3 \text{ V} \pm 0.3 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}, 1.8 \text{ V} \pm 0.15 \text{ V}, 1.5 \pm 0.1 \text{ V}, \text{ and } 1.2 \text{ V}$$

The JEDEC standards also specify the input and output logic voltage levels for these power-supply voltages.

4.16.1 5-V Tolerant Inputs

5-V TTL devices and CMOS devices have been discussed in earlier sections. Because of the popularity of the 74TTL logic family, 74HCT/ACT/AHCT/FCT CMOS logic devices have been developed by the manufacturers which enabled the designers to make use of the advantages of both devices by mixing them in systems.

With the lowering of supply-voltage in CMOS logic to 3.3 V and below, the problem of 5-V voltage devices with the earlier 5-V devices of TTL and CMOS has become more serious. A CMOS gate greater than V_{CC} is not tolerated. When two different logic voltage families are mixed, the voltage appearing at the input of a low-voltage CMOS device may exceed its power rating, damaging the low-voltage CMOS device. For example, a 5-V CMOS device may produce 4.0 volts which the 3.3 V devices will not be able to tolerate. To overcome this problem, devices are produced which can tolerate 5 V inputs. These devices are referred to as 1V

Read To Output Active Time (t_{RDV})

This is the minimum time delay between the beginning of the read pulse and the active state (from the high-impedance state).

Chip-Select To Output Valid Time (t_{CO})

This is the maximum time delay between the beginning of the chip-select pulse and the data outputs.

Chip-Select To Output Active Time (t_{CA})

This is the minimum time delay between the beginning of the chip-select pulse and the active state.

Output Tristate From Read (t_{OTD})

This is the maximum time delay between the end of the read pulse and the output impedance state.

Data Hold Time (t_{OHA})

This is the minimum time for which the valid data is available at the data outputs after the read cycle. The write- and read-cycle timings of a typical memory chip are given in Table 1

TECHNICAL TERMS

Important *Technical Terms* have been clearly defined for better understanding of the concepts involved.

ILLUSTRATIONS

A large number of *Illustrations*, totalling to 551, are provided at suitable locations to illustrate the concepts clearly for better understanding of the topic.

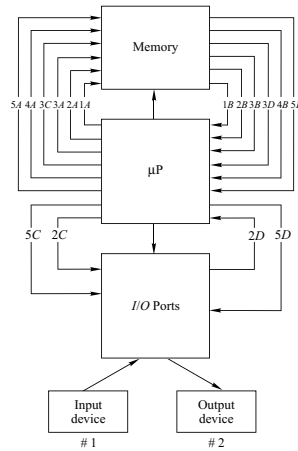


Fig. 13.7 Execution Sequence of the Sample Program

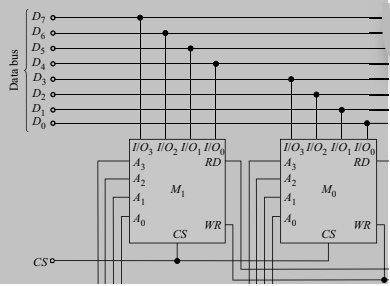
Example 11.3

Obtain a 16×8 memory using 16×4 memory ICs.

Solution

Since the word size required is $n = 8$ and the word size of the available IC is $N = 4$, the required to obtain the desired memory.

Since each chip can store 16 4-bit words and we want to store 16 8-bit words, each chip is used to store 8 4-bit words. Figure 11.6 shows the relevant connections of the two chips. Here, we have assumed that the high-order four bits (D_7, D_6, D_5, D_4) of each 8-bit word are located in memory M_1 and the lower order four bits (D_3, D_2, D_1, D_0) are located in memory M_0 .



SOLVED EXAMPLES

Solved Examples, numbering 223, spread suitably through each chapter, are provided at appropriate locations, to aid in clear understanding of the text material.

AVAILABLE ICs

Commercially Available ICs for each digital function is provided to help understand their functions and options available and allow a proper selection for design.

74S288 TTL PROM

The 74S288 is a 256 bit Schottky TTL PROM organised as 32×8 bits. Its logic diagram is shown in Fig. 11.14. It is available in 16-pin DIP and has one enable (\overline{G}) input terminal which is active LOW. When the device is enabled (\overline{G} LOW), the outputs ($O_0 - O_7$) represent the contents of the address input. When disabled (\overline{G} HIGH), the outputs go to the OFF (high-impedance) state. A HIGH may be programmed into any select the titanium-tungsten fuse which requires 10.5 V for programming.

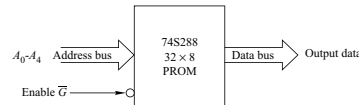


Fig. 11.14 Logic Diagram of 74S288 32×8 Schottky TTL PROM

27C010 OTP EPROM

Figure 11.15 shows the logic diagram of 27C010-1 Megabit OTP EPROM. It is CMOS read-only memory (OTP EPROM) organised as $128 \text{ K} \times 8$ bits. It has Enable (\overline{CE}), Output Enable (\overline{OE}), and Program Store (\overline{PGM}).

GLOSSARY

- Asynchronous sequential circuit** A sequential circuit whose behaviour depends on which input signals change. It is event driven and does not require clock pulses.
- Bit time** Amount of time to transmit a single bit.
- Bouncing** Moving back and forth between two states before reaching a final state.
- Bounce-elimination circuit** A circuit that eliminates the effect of switch bounce.
- Characteristic table** A table describing operation of a FLIP-FLOP.
- Chatterless switch** A switch in which the bouncing effect has been eliminated.
- Clear** Setting the contents of a FLIP-FLOP or a circuit containing FLIP-FLOPs to a known state.
- Clear input** The input used for clearing a digital circuit.
- Clock** A train of pulses of usually constant frequency that synchronize the operation of sequential circuit including a microprocessor based system.
- Clock cycle** The interval between successive positive or negative transitions in a clock signal.
- Clocked FLIP-FLOP** A FLIP-FLOP that responds to the data inputs only at the appropriate clock signal.
- Clock frequency** The number of clock cycles per second.
- Clocked sequential circuit** The sequential circuits whose operation is synchronized with clock pulses, between which no changes of state occur.
- Counter** A digital circuit that can count the number of pulses.
- Data** Information in digital (binary) form.
- Debouncing switch** Same as chatterless switch.
- D-type FLIP-FLOP** A FLIP-FLOP whose output follows the input when triggered by a clock pulse.
- Edge-triggered FLIP-FLOP** A FLIP-FLOP whose state changes on the rising (negative) edge of a clock pulse.

GLOSSARY

At the close of each chapter, Glossary of important terms, totalling to 542, is provided. It gives a list of key terms involved along with their definitions.

REVIEW QUESTIONS

Short answer Review Questions are provided at the end of each chapter in sufficient number, totalling to 293, for testing the understanding of the concepts introduced in the chapter. Their answers are available in Appendix-C.

REVIEW QUESTIONS

- 1.1 Ordinary electrical switch is _____ device. (analog/digital)
- 1.2 A train of pulses is _____ signal. (analog/digital)
- 1.3 The output of an AND gate is high if and only if all its inputs are _____
- 1.4 If one of the inputs to an OR gate is high its output will be _____
- 1.5 An AND gate output will always differ from an OR gate output for the same inputs.
- 1.6 An OR gate is DISABLED by connecting one of its inputs to logic level _____
- 1.7 To ENABLE an OR gate, one of its inputs is connected to logic level _____
- 1.8 To INHIBIT (or DISABLE) an AND gate one of its inputs is connected to logic level _____ (0/1)
- 1.9 To ENABLE an AND gate one of its inputs is connected to logic level _____
- 1.10 An AND gate is ENABLED by connecting one of its inputs to logic level _____
- 1.11 To DISABLE a NOR gate one of its inputs needs to be connected to logic level _____
- 1.12 One of the inputs of an AND gate is labelled as ENABLE. This control input is _____ (active-low/active-high)
- 1.13 One of the inputs of a NOR gate is labelled as ENABLE. This control input is _____ (active-low/active-high)
- 1.14 The universal gates cannot be used as inverters. (True/False)
- 1.15 EXCLUSIVE-OR and EXCLUSIVE-NOR gates can be used as inverters. (True/False)
- 1.16 An EX-OR gate can be used to compare digital signals. (True/False)
- 1.17 If one of the inputs of an EX-OR gate is high, its output will be _____ (input/inverse of other input)
- 1.18 The number of rows in a truth table of 4 variables is _____.
- 1.19 A 3-input NOR gate is required to detect the simultaneous occurrence of a state. Its output is _____ (active-low/active-high)
- 1.20 The number of 3-input NAND gates in a 14-pin IC is _____.
- 1.21 The minimum number of bits required to distinguish 108 distinct objects is _____.

PROBLEMS

- 2.1 Determine the decimal numbers represented by the following binary number
- | | | | |
|------------|--------------|---------------|-----|
| (a) 111001 | (c) 11111110 | (e) 1101.0011 | (g) |
| (b) 101001 | (d) 1100100 | (f) 1010.1010 | |
- 2.2 Determine the binary numbers represented by the following decimal number
- | | | |
|---------|-----------|-----------|
| (a) 37 | (c) 15 | (e) 11.75 |
| (b) 255 | (d) 26.25 | (f) 0.1 |
- 2.3 Add the following groups of binary numbers:
- | | |
|---|--|
| (a) $\begin{array}{r} 1011 \\ + 1101 \\ \hline \end{array}$ | (b) $\begin{array}{r} 1010.1101 \\ + 101.01 \\ \hline \end{array}$ |
|---|--|
- 2.4 Perform the following subtractions using 2's complement method:
- | | | |
|-------------------|-------------------|---------------------------|
| (a) 01000 - 01001 | (b) 01100 - 00011 | (c) 0011.1001 - 0001.1110 |
|-------------------|-------------------|---------------------------|
- 2.5 Convert the following numbers from decimal to octal and then to binary. Compare the binary numbers obtained directly from the decimal number
- | | | |
|---------|---------|------------|
| (a) 375 | (b) 249 | (c) 27.125 |
|---------|---------|------------|
- 2.6 Convert the following binary numbers to octal and then to decimal. Compare the decimal numbers obtained directly from the binary number
- | | | |
|---------------------|---------------------|--------------|
| (a) 11011100.101010 | (b) 01010011.010101 | (c) 10110011 |
|---------------------|---------------------|--------------|

PRACTICE PROBLEMS

Each chapter contains a set of *Practice Problems*, totalling to 315, which require application of ideas and concepts discussed in the book. Answers for some of the selected Problems are provided in Appendix-D.

BIBLIOGRAPHY

Bibliography, provided at the end of the book, gives some useful references.

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ONLINE RESOURCES

Online webaddresses are provided for some of the prominent IC manufacturers and distributors from where useful further information can be obtained about various products.

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